

Description

LPN2010C use advanced FSMOS™ technology to provide low $R_{DS(on)}$, low gate charge, fast switching and excellent avalanche characteristics. This device is specially designed to get better ruggedness and suitable to use in Synchronous-rectification applications.

◆ $V_{DS,min}$	100V
◆ $I_{D,pulse}$	140A
◆ $R_{DS(ON),max}@V_{GS}=10V$	20mΩ
◆ Q_g	19.8nC

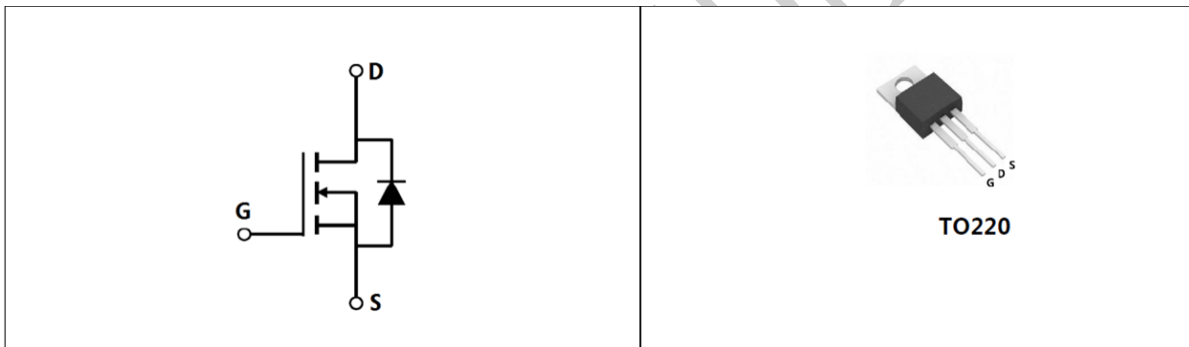
Features

- Low $R_{DS(on)}$ &FOM
- Extremely low switching loss
- Excellent stability and uniformity
- Fast switching and soft recovery

Applications

- Consumer electronic power supply
- Motor control
- Synchronous-rectification
- Isolated DC/DC convertor
- Invertors

Schematic and Package Information



Schematic Diagram

Pin Assignment Top View

Ordering Information

Package	Units/Tube	Tubes/Inner Box	Units/Inner Box	Inner Box/Carton Box	Units/Carton Box
TO220	50	20	1000	6	6000

Product Information

Product	Package	Pb Free	RoHS	Halogen Free
LPN2010C	TO220	yes	yes	yes

Absolute Maximum Rating at $T_j=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Value	Unit
Drain source voltage	V_{DS}	100	V
Gate source voltage	V_{GS}	± 20	V
Continuous drain current ¹⁾	I_D	50	A
Pulsed drain current ²⁾	$I_{D,pulse}$	140	A
Power dissipation ³⁾	P_D	80	W
Single pulsed avalanche energy ⁵⁾	E_{AS}	30	mJ
Operation and storage temperature	T_{stg}, T_j	-55 to 150	$^\circ\text{C}$

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal resistance, junction-case	$R_{\theta JC}$	0.38	$^\circ\text{C/W}$
Thermal resistance, junction-ambient ⁴⁾	$R_{\theta JA}$	62.5	$^\circ\text{C/W}$

Electrical Characteristics at $T_j=25^\circ\text{C}$ unless otherwise specified

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Drain-source breakdown voltage	BV_{DSS}	100			V	$V_{GS}=0V, I_D=250\mu A$
Gate threshold voltage	$V_{GS(th)}$	1.0		2.5	V	$V_{DS}=V_{GS}, I_D=250\mu A$
Drain-source on-state resistance	$R_{DS(on)}$		17	20	m Ω	$V_{GS}=10V, I_D=8A$
Drain-source on-state resistance	$R_{DS(on)}$		12	26	m Ω	$V_{GS}=4.5V, I_D=6A$
Gate-source leakage current	I_{GSS}			100	nA	$V_{GS}=20V$
				-100		$V_{GS}=-20V$
Drain-source leakage current	I_{DSS}			1	μA	$V_{DS}=100V, V_{GS}=0V$

Dynamic Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Input capacitance	C_{iss}		1190.6		pF	$V_{GS}=0V,$ $V_{DS}=50V,$ $f=1MHz$
Output capacitance	C_{oss}		194.6		pF	
Reverse transfer capacitance	C_{rss}		4.1		pF	
Turn-on delay time	$T_{d(on)}$		17.8		nS	$V_{GS}=10V,$ $V_{DS}=50V,$ $R_G=2.2\Omega,$ $I_D=10A$
Rise time	t_r		3.9		nS	
Turn-off delay time	$T_{d(off)}$		33.5		nS	
Fall time	t_f		3.2		nS	

Gate Charge Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Total gate charge	Q_g		19.8		nC	$I_D=8A,$ $V_{DS}=50V,$ $V_{GS}=10V$
Gate-source charge	Q_{gs}		2.4		nC	
Gate-drain charge	Q_{gd}		5.3		nC	
Gate plateau voltage	$V_{plateau}$		3.2		V	

Body Diode Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Diode forward current	I_S			50	A	$V_{GS} < V_{th}$
Pulsed source current	I_{SP}			140	A	
Diode forward voltage	V_{SD}			1.3	V	$I_S = 8A, V_{GS} = 0V$
Reverse recovery time	t_{rr}		50.2		nS	$I_S = 8A,$ $di/dt = 100A/\mu S$
Reverse recovery charge	Q_{rr}		95.1		nC	
Peak reverse recovery current	I_{rrm}		2.5		A	

Note

- 1) Calculated continuous current based on maximum allowable junction temperature.
- 2) Repetitive rating; pulse width limited by max. junction temperature.
- 3) P_d is based on max. junction temperature, using junction-case thermal resistance.
- 4) The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_a = 25^\circ C$.
- 5) $V_{DD} = 50V, R_G = 25 \Omega, L = 0.3mH$, starting $T_j = 25^\circ C$

Electrical Characteristics Diagrams

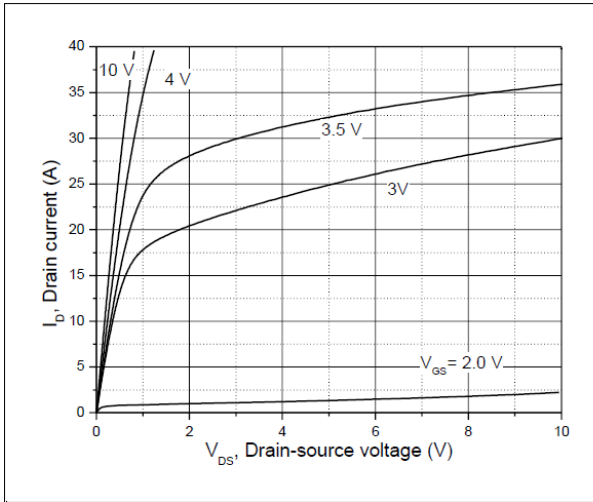


Figure 1, Typ. Output characteristics

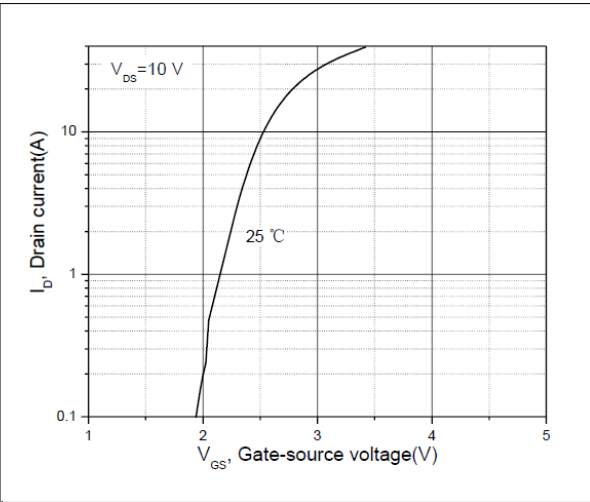


Figure 2, Typ. Transfer characteristics

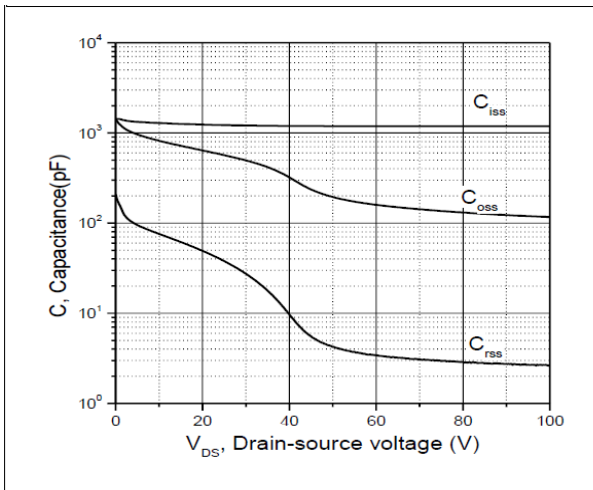


Figure 3, Typ. capacitances

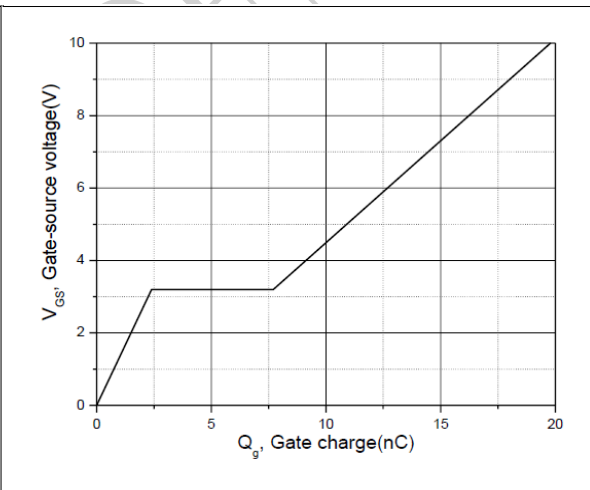


Figure 4, Typ. gate charge

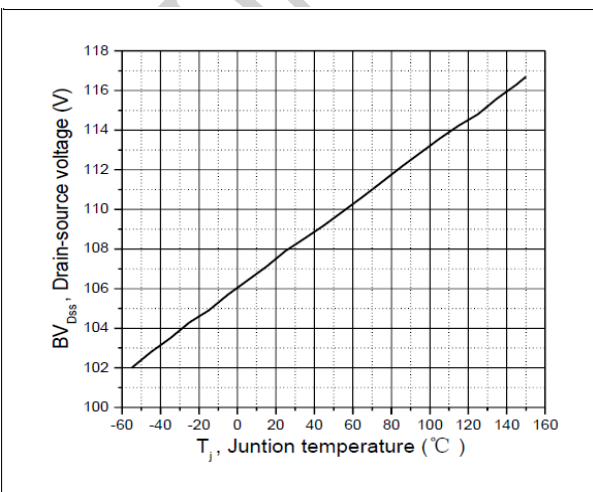


Figure 5, Drain-source breakdown voltage

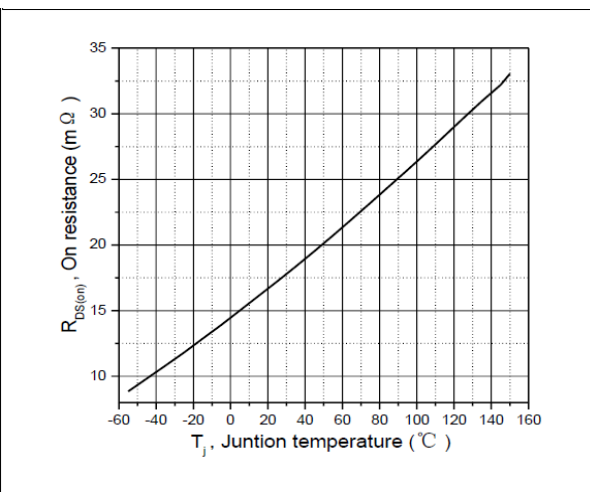


Figure 6, Drain-source on-state resistance

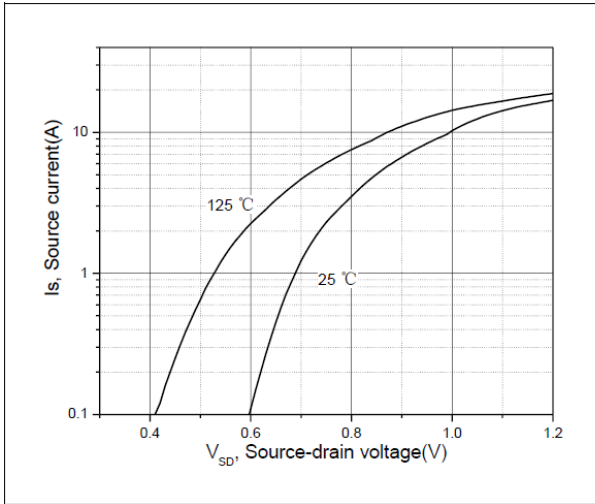


Figure 7, Forward characteristics of body diode

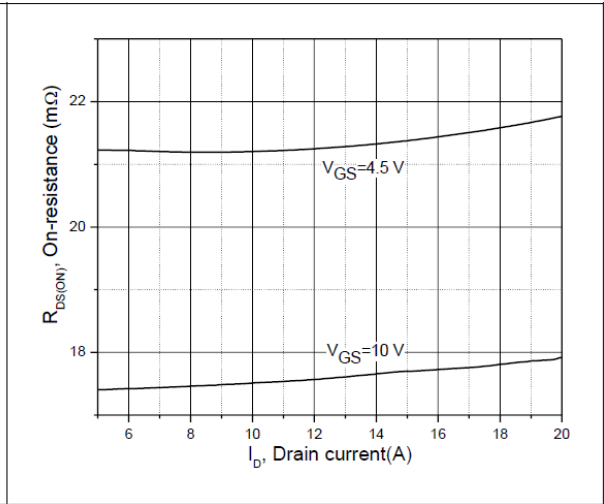


Figure 8, Drain-source on-state resistance

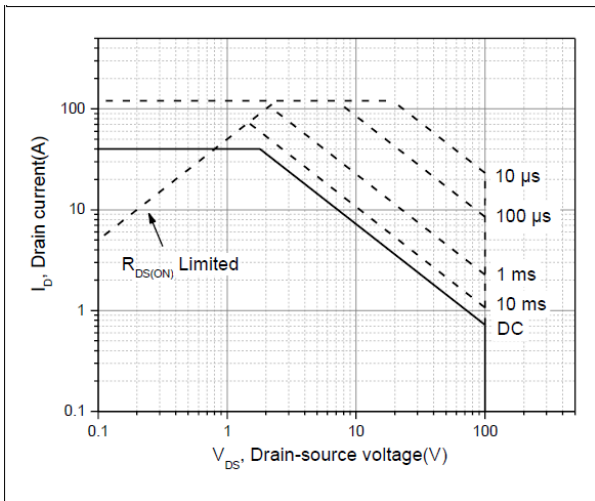


Figure 9, Safe operation area $T_C=25^\circ\text{C}$

Test circuits and waveforms

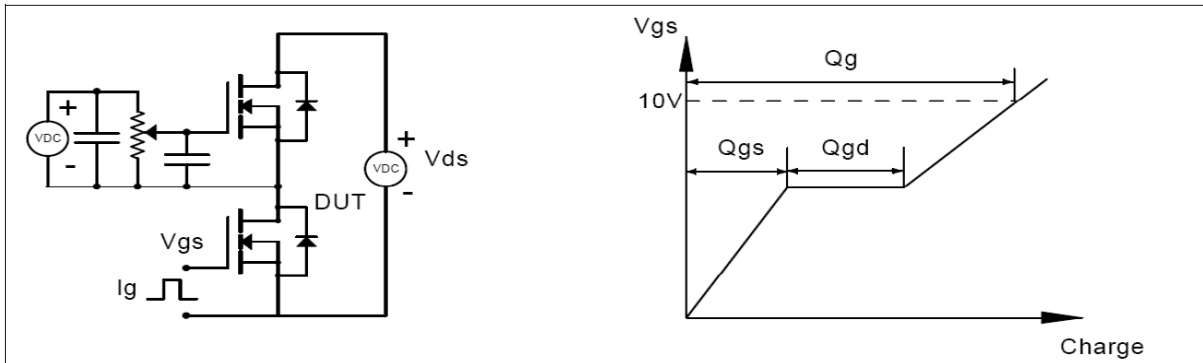


Figure 1, Gate charge test circuit & waveform

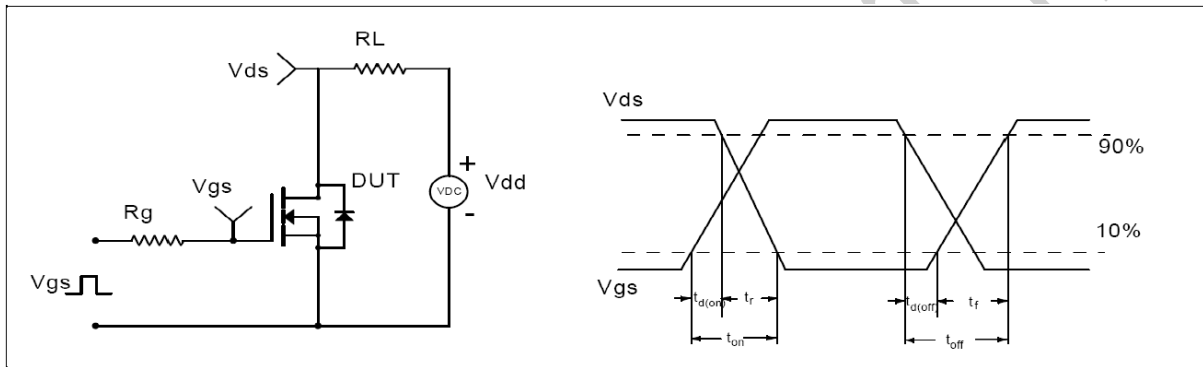


Figure 2, Switching time test circuit & waveforms

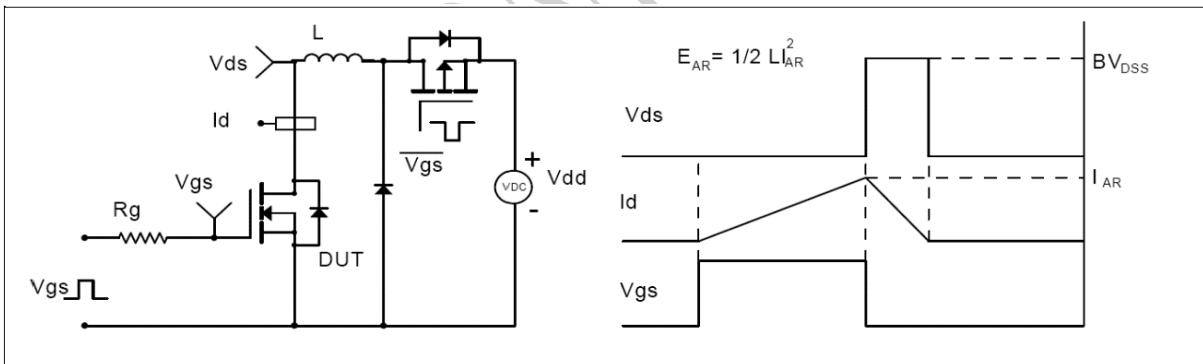


Figure 3, Unclamped inductive switching (UIS) test circuit & waveforms

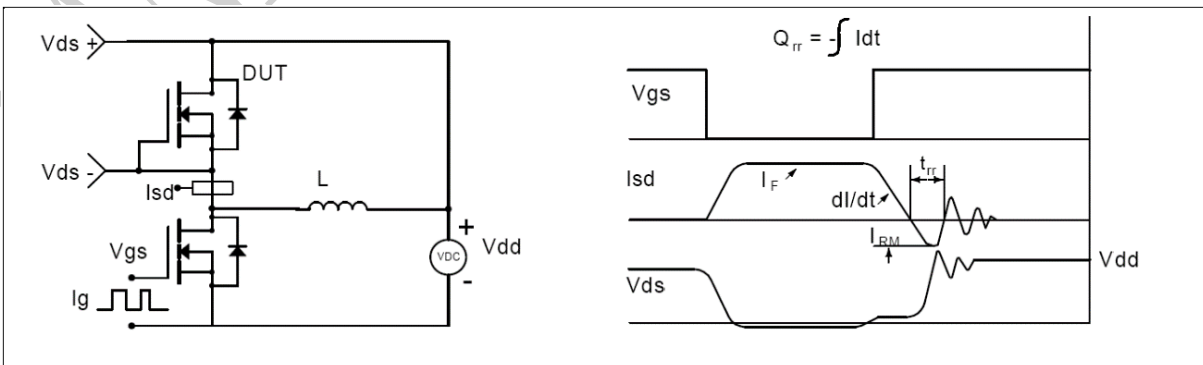


Figure 4, Diode reverse recovery test circuit & waveforms

